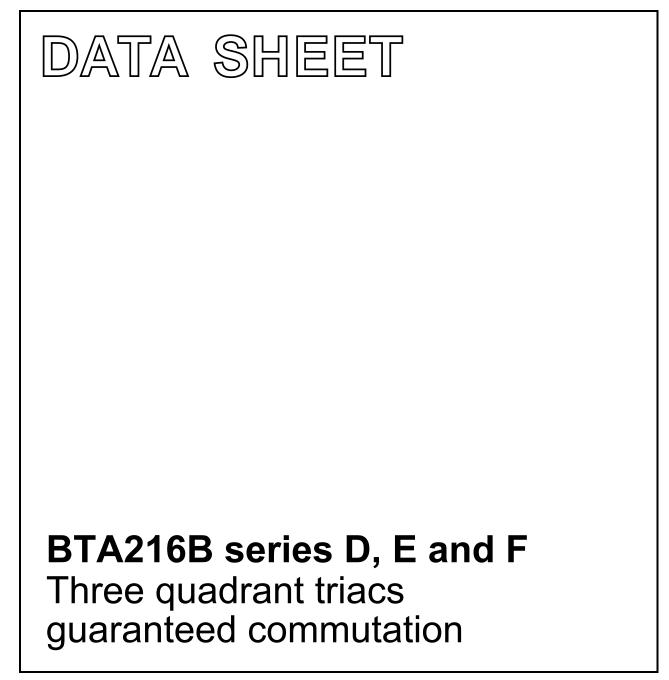
DISCRETE SEMICONDUCTORS



Product specification

July 2018



BTA216B series D, E and F

GENERAL DESCRIPTION

Passivated guaranteed commutation triacs in a plastic envelope suitable for surface mounting, intended for use in motor control circuits or with other highly inductive loads. These devices balance the requirements of commutation performance and gate sensitivity. The "sensitive gate" E series and "logic level" D series are intended for interfacing with low power drivers, including micro controllers.

PINNING - SOT404

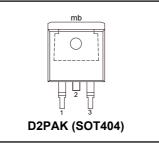
QUICK REFERENCE DATA

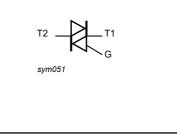
SYMBOL	PARAMETER	MAX.	UNIT
V _{drm} I _{t(rms)} I _{tsm}	BTA216B- BTA216B- BTA216B- BTA216B- Repetitive peak off-state voltages RMS on-state current Non-repetitive peak on-state current	600D 600E 600F 600 16 140	V A A
	Current		

PIN CONFIGURATION

SYMBOL

PIN	DESCRIPTION	
1	main terminal 1	
2	main terminal 2	
3	gate	
mb	main terminal 2	





LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
	Repetitive peak off-state voltages		-	600 ¹	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _{mp} ≤ 99 °C	-	16	А
I _{TSM}	Non-repetitive peak on-state current	full sine wave; $T_j = 25$ °C prior to surge t = 20 ms t = 16.7 ms	- -	140 150	A
l²t dI _⊤ /dt	I ² t for fusing Repetitive rate of rise of on-state current after triggering		-	98 100	A A²s A/µs
$\begin{matrix} I_{GM} \\ P_{GM} \\ P_{G(AV)} \end{matrix}$	Peak gate current Peak gate power Average gate power	over any 20 ms period	- - -	2 5 0.5	A W W
T _{stg} T _j	Storage temperature Operating junction temperature		-40 -	150 125	ĴĴ Ĵ

¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15 $A/\mu s$.

BTA216B series D, E and F

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-mb} R _{th j-a}	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle minimum footprint, FR4 board	- - -	- - 55	1.2 1.7 -	K/W K/W K/W

STATIC CHARACTERISTICS

 $T_j = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.		UNIT
		BTA216B-		D	E	F	
I _{GT}	Gate trigger current ²	V _D = 12 V; I _T = 0.1 A T2+ G+ T2+ G- T2- G-	- - -	5 5 5	10 10 10	25 25 25	mA mA mA
IL.	Latching current	V _D = 12 V; I _{GT} = 0.1 A T2+ G+ T2+ G- T2- G-	- - -	15 25 25	25 30 30	30 40 40	mA mA mA
I _H	Holding current	$V_{\rm D} = 12 \text{ V}; \text{ I}_{\rm GT} = 0.1 \text{ A}$	-	15	25	30	mA
					D, E, F		
V _T V _{GT}	On-state voltage Gate trigger voltage		- - 0.25		1.5 1.5 -		V V V
I _D	Off-state leakage current	$\begin{bmatrix} T_j = 125 \ ^{\circ}C \\ V_D = V_{DRM(max)}; \ T_j = 125 \ ^{\circ}C \end{bmatrix}$	-		0.5		mA

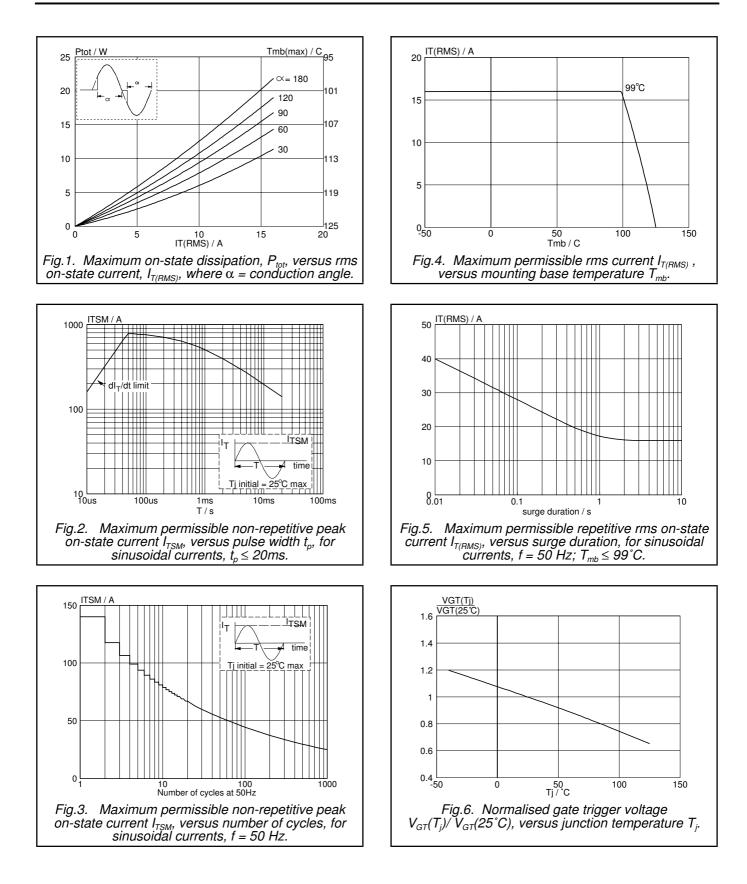
DYNAMIC CHARACTERISTICS

 $T_i = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.		MAX.	UNIT
		BTA216B-	D	E	F		
dV _D /dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(max)};$ $T_j = 110 °C; exponential$	30	60	70	-	V/µs
dl _{com} /dt	Critical rate of change of commutating current	waveform; gate open circuit $V_{DM} = 400 \text{ V}; \text{ T}_{j} = 125 \text{ °C};$ $I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 10V/\mu s; gate$ open circuit	2.5	6.2	18	-	A/ms
dl _{com} /dt	Critical rate of change of commutating current	$V_{DM} = 400 \text{ V}; \text{ T}_{j} = 125 \text{ °C};$ $I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 0.1 \text{ V}/\mu\text{s}; \text{ gate}$ open circuit	12	20	50	-	A/ms

² Device does not trigger in the T2-, G+ quadrant.

BTA216B series D, E and F



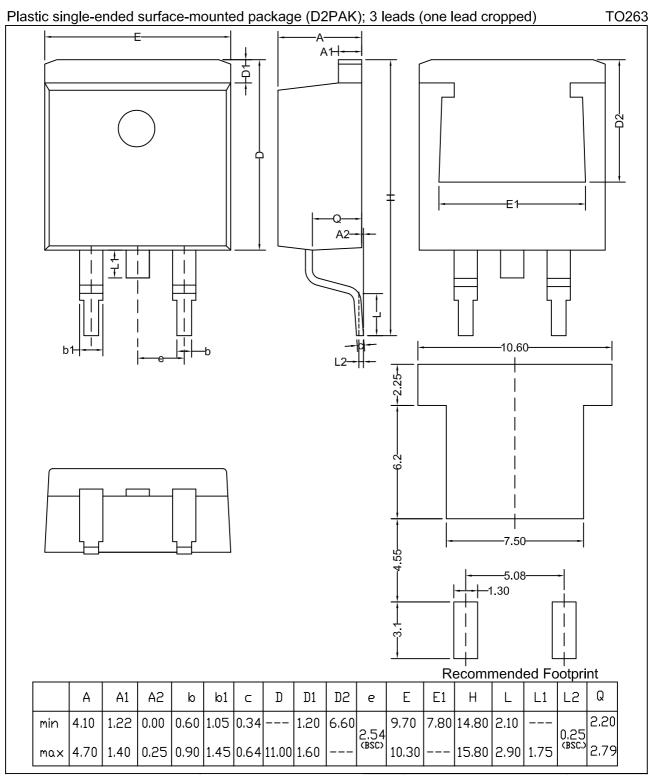
BTA216B series D, E and F

Three quadrant triacs guaranteed commutation

IT / A IGT(Tj) IGT(25℃) 50 Tj = 125 C Tj = 25 C 3 — T2+ G+ — T2+ Gtyp ma - T2- G-40 2.5 Vo = 1.195 V Rs = 0.018 Ohms 2 30 1.5 20 1 10 0.5 0 L 0 0 1.5 VT / V 150 0.5 2 2.5 3 -50 0 тј/℃ 100 1 Fig.7. Normalised gate trigger current $I_{GT}(T_j)/I_{GT}(25^{\circ}C)$, versus junction temperature T_{j} . Fig.10. Typical and maximum on-state characteristic. 10 _____(K/W) IL(Tj) IL(25°C) 3 25 1 bidirectional 2 0.1 1.5 → ^tp → 1 0.01 0.5 0.001 – 10us 0 -50 0.1ms 10ms 0.1s 1s 10s 50 Tj /℃ 100 1ms 0 150 tp/s Fig.8. Normalised latching current $I_L(T_i)/I_L(25^{\circ}C)$, Fig.11. Transient thermal impedance $Z_{th j-mb}$, versus versus junction temperature T_{i} pulse width $t_{\rm p}$. dlcom/dt (A/ms) IH(Tj) 100 3 IH(25°C F TYPE E TYPE D TYPE 2.5 2 10 1.5 1 0.5 1 0 -50 50 Tj /℃ 20 40 60 100 120 140 100 150 80 Tj/°C 0 Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}C)$, versus junction temperature T_j . Fig.12. Mimimum, critical rate of change of commutating current dI_{com}/dt versus junction temperature, $dV_{com}/dt = 10V/\mu s$.

BTA216B series D, E and F

MECHANICAL DATA



Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.ween-semi.com</u>.

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